CD74HCT574-Q1 HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP 3-STATE, POSITIVE-EDGE TRIGGERED

SCLS570A - FEBRUARY 2004 - REVISED APRIL 2008

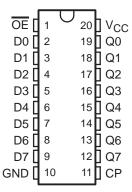
- Qualified for Automotive Applications
- Buffered Inputs
- Common 3-State Output-Enable Control
- 3-State Outputs
- Bus-Line Driving Capability
- Typical Propagation Delay (Clock to Q): 15 ns at V_{CC} = 5 V, C_L = 15 pF, T_A = 25°C
- Fanout (Over Temperature Range)
 - Standard Outputs ... 10 LSTTL Loads
 - Bus Driver Outputs ... 15 LSTTL Loads
- Balanced Propagation Delay and Transition Times

description/ordering information

The CD74HCT574 is an octal D-type flip-flop with 3-state outputs and the capability to drive 15 LSTTL loads. The eight edge-triggered flip-flops enter data into their registers on the low-to-high transition of the clock (CP). The output enable (\overline{OE}) controls the 3-state outputs and is independent of the register operation. When \overline{OE} is high, the outputs are in the high-impedance state.

- Significant Power Reduction Compared to LSTTL Logic ICs
- V_{CC} Voltage = 4.5 V to 5.5 V
- Direct LSTTL Input Logic Compatibility,
 V_{IL} = 0.8 V (Max), V_{IH} = 2 V (Min)
- CMOS Input Compatibility, $I_I \le 1 \mu A$ at V_{OL} , V_{OH}

M OR PW PACKAGE (TOP VIEW)



ORDERING INFORMATION†

TA	PACK	AGE‡	ORDERABLE PART NUMBER	TOP-SIDE MARKING
400C to 4050C	SOIC - M	Tape and reel	CD74HCT574QM96Q1	HCT574Q
-40°C to 125°C	TSSOP - PW	Tape and reel	CD74HCT574QPWRQ1	HCT574Q

[†] For the most current package and ordering information, see the Package Option Addendum at the end of this document, or see the TI web site at http://www.ti.com.



Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



[‡] Package drawings, thermal data, and symbolization are available at http://www.ti.com/packaging.

CD74HCT574-Q1 HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP **3-STATE, POSITIVE-EDGE TRIGGERED** SCLS570A – FEBRUARY 2004 – REVISED APRIL 2008

FUNCTION TABLE

	INPUTS	OUTPUT	
OE	СР	D	Q
L	↑	Н	Н
L	↑	L	L
L	L	Χ	Q ₀
Н	Х	Х	Z

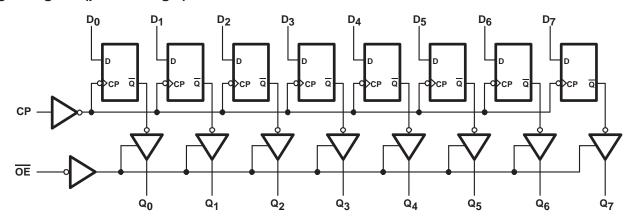
NOTE: H = High voltage level (steady state) L = Low voltage level (steady state)

X = Don't care

 \uparrow = Transition from low to high level Q_0 = Level before the indicated steady-state conditions were established

Z = High-impedance state

logic diagram (positive logic)



CD74HCT574-Q1 HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP 3-STATE, POSITIVE-EDGE TRIGGERED SCLS570A - FEBRUARY 2004 - REVISED APRIL 2008

absolute maximum ratings over operating free-air temperature range (unless otherwise noted)†

Supply voltage range, V _{CC} (see Note 1)	0.5 V to 7 V
Input clamp current, I_{IK} ($V_I < -0.5 \text{ V or } V_I > V_{CC} + 0.5 \text{ V}$)	
Output clamp current, I_{OK} ($V_O < -0.5 \text{ V or } V_O > V_{CC} + 0.5 \text{ V}$)	±20 mA
Drain current per output, I_O ($V_O > -0.5 \text{ V}$ or $V_O < V_{CC} + 0.5 \text{ V}$)	±35 mA
Output source or sink current per output, I_O ($V_O > -0.5$ V or $V_O < V_{CC} + 0.5$ V)	±25 mA
Continuous current through V _{CC} or GND, I _{CC}	±50 mA
Package thermal impedance, θ _{JA} (see Note 2): M package	58°C/W
PW package	69°C/W
Maximum junction temperature, T _J	150°C
Lead temperature (during soldering):	
At distance $1/16 \pm 1/32$ inch $(1,59 \pm 0,79 \text{ mm})$ from case for 10 s max	300°C
Storage temperature range, T _{stq}	-65°C to 150°C

[†] Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

NOTES: 1. All voltages referenced to GND unless otherwise specified.

recommended operating conditions (see Note 3)

		М	IN	MAX	UNIT
Vcc	Supply voltage	4	.5	5.5	V
VIH	High-level input voltage $V_{CC} = 4.5 \text{ V}$ to	5.5 V	2		V
VIL	Low-level input voltage $V_{CC} = 4.5 \text{ V}$ to	5.5 V		0.8	V
VI	Input voltage		0	VCC	V
VO	Output voltage		0	VCC	V
	V _{CC} = 2 V		0	1000	
t _t	Input transition (rise and fall) time $V_{CC} = 4.5 \text{ V}$		0	500	ns
	V _{CC} = 6 V		0	400	
TA	Operating free-air temperature	_	40	125	°C

NOTE 3: All unused inputs of the device must be held at V_{CC} or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.



^{2.} The package thermal impedance is calculated in accordance with JESD 51-7.

CD74HCT574-Q1 HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP **3-STATE, POSITIVE-EDGE TRIGGERED** SCLS570A – FEBRUARY 2004 – REVISED APRIL 2008

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CO	NDITIONS	lo (mA)	vcc	Т,	4 = 25°C	;	T _A = -40°C TO 125°C		UNIT	
			(mA)		MIN	TYP	MAX	MIN	MAX		
.,,	V VV	CMOS loads	-0.02	4.5 V	4.4			4.4		.,	
VOH	$V_I = V_{IH}$ or V_{IL}	TTL loads	-6	4.5 V	3.98			3.7		V	
.,,	V VV	CMOS loads	0.02	4.5 V			0.1		0.1	.,	
V _{OL}	$V_I = V_{IH}$ or V_{IL}	TTL loads	6	4.5 V			0.26		0.4	V	
lį	$V_I = V_{CC}$ or GND		0	5.5 V			±0.1		±1	μΑ	
loz	$V_I = V_{IL} \text{ or } V_{IH},$	$V_O = V_{CC}$ or GND		6 V			±0.5		±10	μΑ	
ICC	$V_I = V_{CC}$ or GND		0	5.5 V			8		160	μΑ	
ΔlCC	$V_{I} = V_{CC} - 2.1 V,$	See Note 4		4.5 V to 5.5 V		100	360		490	μΑ	
C _{IN}	C _L = 50 pF						10		10	pF	
COUT	3-state	_					20		20	pF	

NOTE 4: For dual-supply systems, theoretical worst-case (V_I = 2.4 V, V_{CC} = 5.5 V) specification is 1.8 mA.

HCT input loading

TYPE	INPUT	UNIT LOADS†				
	D0-D7	0.4				
'574	CP	0.75				
	OE	0.6				

 $^{^{\}dagger}$ Unit load is ΔI_{CC} limit specified in electrical characteristics table, e.g., 360 μA max at 25°C.

timing requirements over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

	PARAMETER	Vcc	T _A = 2	25°C	T _A = -	UNIT	
			MIN	MAX	MIN	20 N 24 18	
f _{max}	Maximum clock frequency	4.5 V	30		20		MHz
t _W	Clock pulse duration	4.5 V	16		24		ns
t _{su}	Setup time, data before clock↑	4.5 V	12		18		ns
th	Hold time, data after clock ↑	4.5 V	5		5		ns

CD74HCT574-Q1 HIGH-SPEED CMOS LOGIC OCTAL D-TYPE FLIP-FLOP 3-STATE, POSITIVE-EDGE TRIGGERED SCLS570A - FEBRUARY 2004 - REVISED APRIL 2008

switching characteristics over recommended operating free-air temperature range (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	TO	LOAD	ν _{CC}	T	λ = 25°C	;	T _A = -	UNIT		
	(INPUT)	(OUTPUT)	CAPACITANCE		MIN	TYP	MAX	MIN	MAX		
	CD.	_	C _L = 50 pF	4.5 V			33		50		
^t pd	СР	Q	C _L = 15 pF	5 V		15				ns	
4	t _{dis} $\overline{\text{OE}}$	_	C _L = 50 pF	4.5 V			28		42		
^t dis		Q	C _L = 15 pF	5 V		11				ns	
	ŌĒ		$C_{L} = 50 \text{ pF}$	4.5 V			30		45		
^t en	OE	Q	C _L = 15 pF	5 V		12				ns	
t _t		Q	C _L = 50 pF	4.5 V			12	·	18	ns	
f _{max}	СР		C _L = 15 pF	5 V		60		·		MHz	

operating characteristics, $V_{CC} = 5 \text{ V}$, $T_A = 25^{\circ}\text{C}$, input t_r , $t_f = 6 \text{ ns}$

	PARAMETER	TYP	UNIT
C _{pd}	Power dissipation capacitance (see Note 5)	47	pF

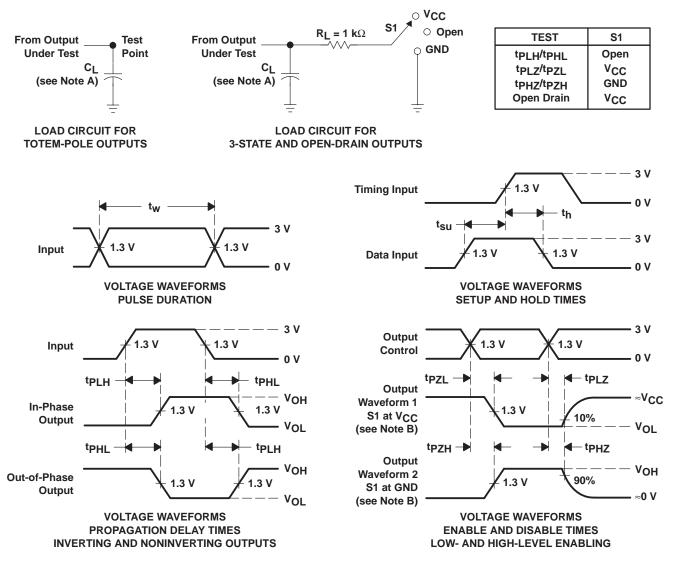
NOTE 5: C_{pd} is used to determine the dynamic power consumption (P_D), per package. $P_D = (C_{PD} \times V_{CC}^2 \times f_I) + \Sigma (C_L \times V_{CC}^2 \times f_O)$ $f_I = \text{input frequency}$

f_O = output frequency

C_L = output load capacitance

V_{CC} = supply voltage

PARAMETER MEASUREMENT INFORMATION



NOTES: A. C_L includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low, except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high, except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR \leq 1 MHz, $Z_O = 50 \Omega$, $t_f \leq 6$ ns. $t_f \leq 6$ ns.
- D. The outputs are measured one at a time, with one input transition per measurement.
- E. All parameters and waveforms are not applicable to all devices.
- F. tpLH and tpHL are the same as tpd.
- G. tpLZ and tpHZ are the same as tdis.
- H. tpzH and tpzL are the same as ten.

Figure 1. Load Circuit and Voltage Waveforms





PACKAGE OPTION ADDENDUM

10-Dec-2020

PACKAGING INFORMATION

www.ti.com

Orderable Device	Status	Package Type	Package Drawing	Pins	Package Qty	Eco Plan	Lead finish/ Ball material	MSL Peak Temp	Op Temp (°C)	Device Marking (4/5)	Samples
CD74HCT574QM96G4Q1	ACTIVE	SOIC	DW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574Q1	Samples
CD74HCT574QPWRG4Q1	ACTIVE	TSSOP	PW	20	2000	RoHS & Green	NIPDAU	Level-1-260C-UNLIM	-40 to 125	HCT574Q1	Samples

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

OBSOLETE: TI has discontinued the production of the device.

(2) RoHS: TI defines "RoHS" to mean semiconductor products that are compliant with the current EU RoHS requirements for all 10 RoHS substances, including the requirement that RoHS substance do not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, "RoHS" products are suitable for use in specified lead-free processes. TI may reference these types of products as "Pb-Free".

RoHS Exempt: TI defines "RoHS Exempt" to mean products that contain lead but are compliant with EU RoHS pursuant to a specific EU RoHS exemption.

Green: TI defines "Green" to mean the content of Chlorine (CI) and Bromine (Br) based flame retardants meet JS709B low halogen requirements of <=1000ppm threshold. Antimony trioxide based flame retardants must also meet the <=1000ppm threshold requirement.

- (3) MSL, Peak Temp. The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.
- (4) There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.
- (5) Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.
- (6) Lead finish/Ball material Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead finish/Ball material values may wrap to two lines if the finish value exceeds the maximum column width.

Important Information and Disclaimer: The information provided on this page represents TI's knowledge and belief as of the date that it is provided. TI bases its knowledge and belief on information provided by third parties, and makes no representation or warranty as to the accuracy of such information. Efforts are underway to better integrate information from third parties. TI has taken and continues to take reasonable steps to provide representative and accurate information but may not have conducted destructive testing or chemical analysis on incoming materials and chemicals. TI and TI suppliers consider certain information to be proprietary, and thus CAS numbers and other limited information may not be available for release.

In no event shall TI's liability arising out of such information exceed the total purchase price of the TI part(s) at issue in this document sold by TI to Customer on an annual basis.





10-Dec-2020

OTHER QUALIFIED VERSIONS OF CD74HCT574-Q1:

Catalog: CD74HCT574

● Enhanced Product: CD74HCT574-EP

Military: CD54HCT574

NOTE: Qualified Version Definitions:

- Catalog TI's standard catalog product
- Enhanced Product Supports Defense, Aerospace and Medical Applications
- Military QML certified for Military and Defense Applications

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Jun-2022

TAPE AND REEL INFORMATION





A0	Dimension designed to accommodate the component width
В0	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
W	Overall width of the carrier tape
P1	Pitch between successive cavity centers

QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE

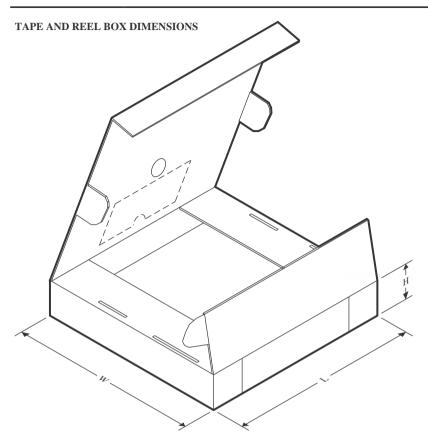


*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
CD74HCT574QM96G4Q1	SOIC	DW	20	2000	330.0	24.4	10.8	13.3	2.7	12.0	24.0	Q1
CD74HCT574QPWRG4Q1	TSSOP	PW	20	2000	330.0	16.4	6.95	7.1	1.6	8.0	16.0	Q1

PACKAGE MATERIALS INFORMATION

www.ti.com 3-Jun-2022



*All dimensions are nominal

Device	Package Type	Package Drawing	Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
CD74HCT574QM96G4Q1	SOIC	DW	20	2000	367.0	367.0	45.0
CD74HCT574QPWRG4Q1	TSSOP	PW	20	2000	356.0	356.0	35.0



SOIC



NOTES:

- 1. All linear dimensions are in millimeters. Dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.43 mm per side.
- 5. Reference JEDEC registration MS-013.



SOIC



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SOIC



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.





SMALL OUTLINE PACKAGE



NOTES:

- 1. All linear dimensions are in millimeters. Any dimensions in parenthesis are for reference only. Dimensioning and tolerancing per ASME Y14.5M.

 2. This drawing is subject to change without notice.

 3. This dimension does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not
- exceed 0.15 mm per side.
- 4. This dimension does not include interlead flash. Interlead flash shall not exceed 0.25 mm per side.
- 5. Reference JEDEC registration MO-153.



SMALL OUTLINE PACKAGE



NOTES: (continued)

6. Publication IPC-7351 may have alternate designs.

7. Solder mask tolerances between and around signal pads can vary based on board fabrication site.



SMALL OUTLINE PACKAGE



NOTES: (continued)

- 8. Laser cutting apertures with trapezoidal walls and rounded corners may offer better paste release. IPC-7525 may have alternate design recommendations.
- 9. Board assembly site may have different recommendations for stencil design.



PW (R-PDSO-G20)

PLASTIC SMALL OUTLINE



NOTES:

- All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
 C. Publication IPC-7351 is recommended for alternate design.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



IMPORTANT NOTICE AND DISCLAIMER

TI PROVIDES TECHNICAL AND RELIABILITY DATA (INCLUDING DATA SHEETS), DESIGN RESOURCES (INCLUDING REFERENCE DESIGNS), APPLICATION OR OTHER DESIGN ADVICE, WEB TOOLS, SAFETY INFORMATION, AND OTHER RESOURCES "AS IS" AND WITH ALL FAULTS, AND DISCLAIMS ALL WARRANTIES, EXPRESS AND IMPLIED, INCLUDING WITHOUT LIMITATION ANY IMPLIED WARRANTIES OF MERCHANTABILITY, FITNESS FOR A PARTICULAR PURPOSE OR NON-INFRINGEMENT OF THIRD PARTY INTELLECTUAL PROPERTY RIGHTS.

These resources are intended for skilled developers designing with TI products. You are solely responsible for (1) selecting the appropriate TI products for your application, (2) designing, validating and testing your application, and (3) ensuring your application meets applicable standards, and any other safety, security, regulatory or other requirements.

These resources are subject to change without notice. TI grants you permission to use these resources only for development of an application that uses the TI products described in the resource. Other reproduction and display of these resources is prohibited. No license is granted to any other TI intellectual property right or to any third party intellectual property right. TI disclaims responsibility for, and you will fully indemnify TI and its representatives against, any claims, damages, costs, losses, and liabilities arising out of your use of these resources.

TI's products are provided subject to TI's Terms of Sale or other applicable terms available either on ti.com or provided in conjunction with such TI products. TI's provision of these resources does not expand or otherwise alter TI's applicable warranties or warranty disclaimers for TI products.

TI objects to and rejects any additional or different terms you may have proposed.

Mailing Address: Texas Instruments, Post Office Box 655303, Dallas, Texas 75265 Copyright © 2022, Texas Instruments Incorporated